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R10000 Superscalar Microprocessor

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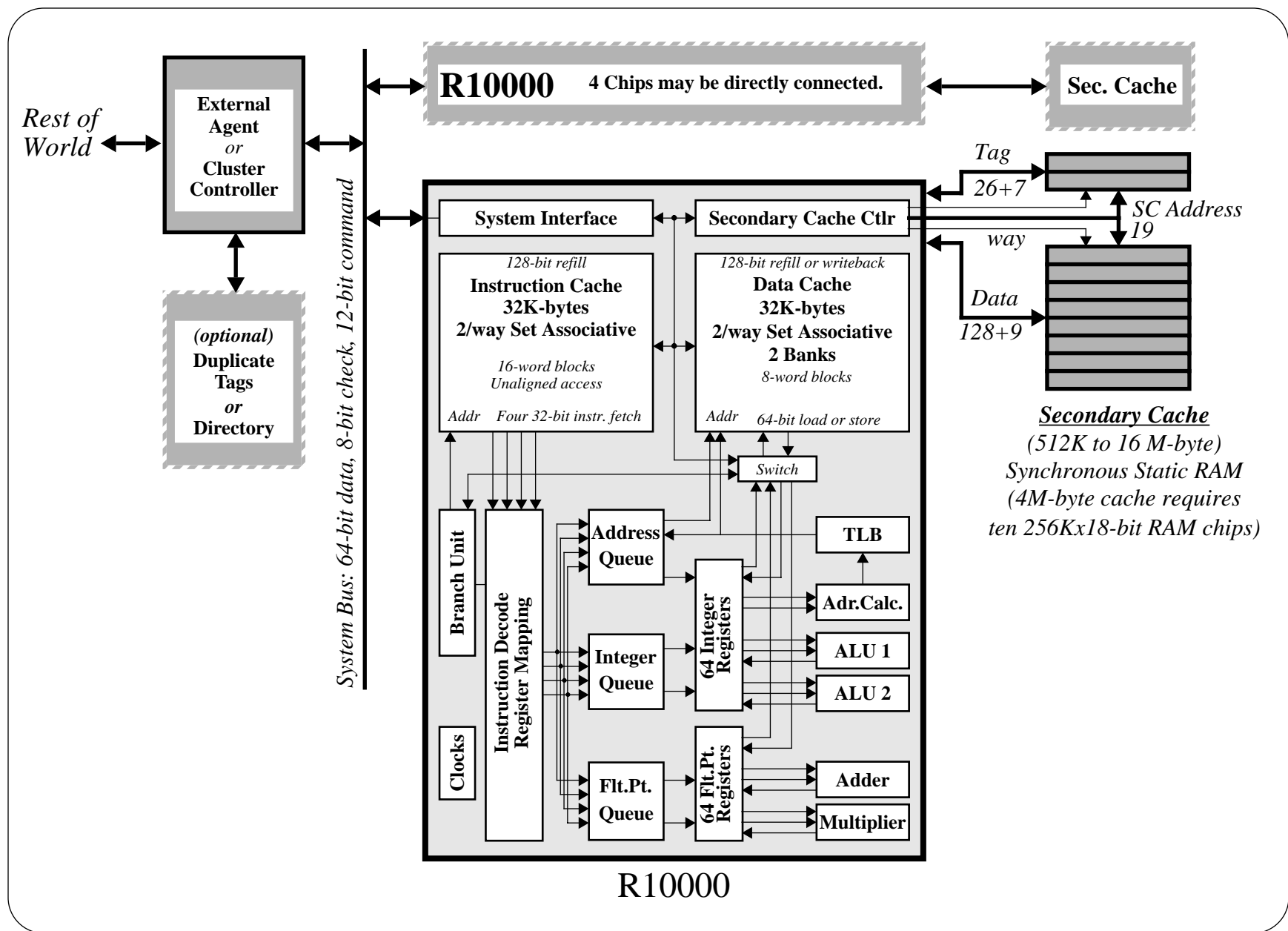
R10000 Superscalar Microprocessor

Ali Ahi, Yung-chin Chen, Robert Conrad, Randal Martin,
Ratan Ramchandani, Mahdi Seddighnezhad, Greg Shippen,
Hong-men Su, Hector Sucar, Nader Vasseghi,
William Voegtli Jr., Kenneth Yeager, Yeffi

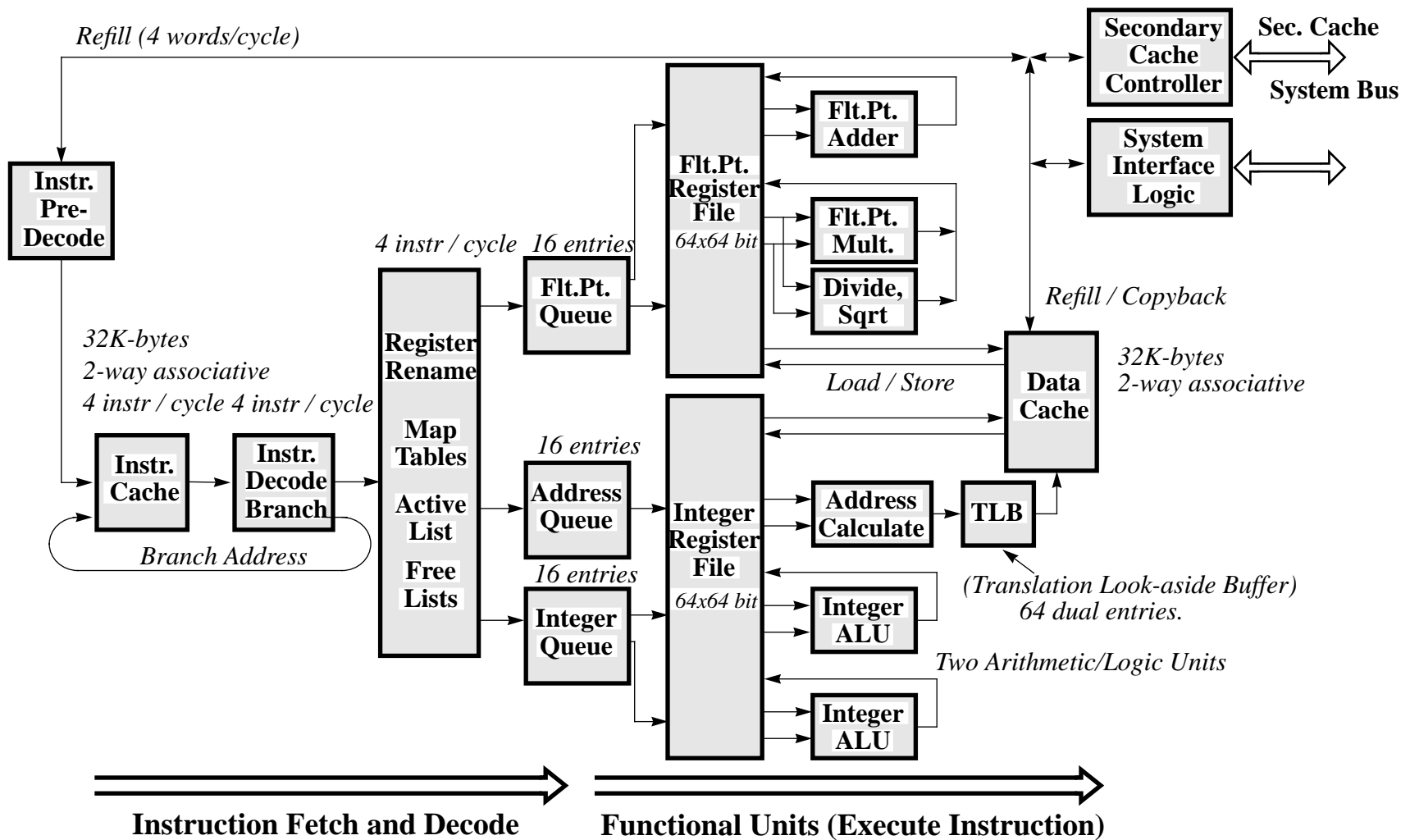
Presentation Outline

- n Architecture of CPU and FPU
- n Memory Hierarchy
- n System Configuration
- n Verification and Design Methods

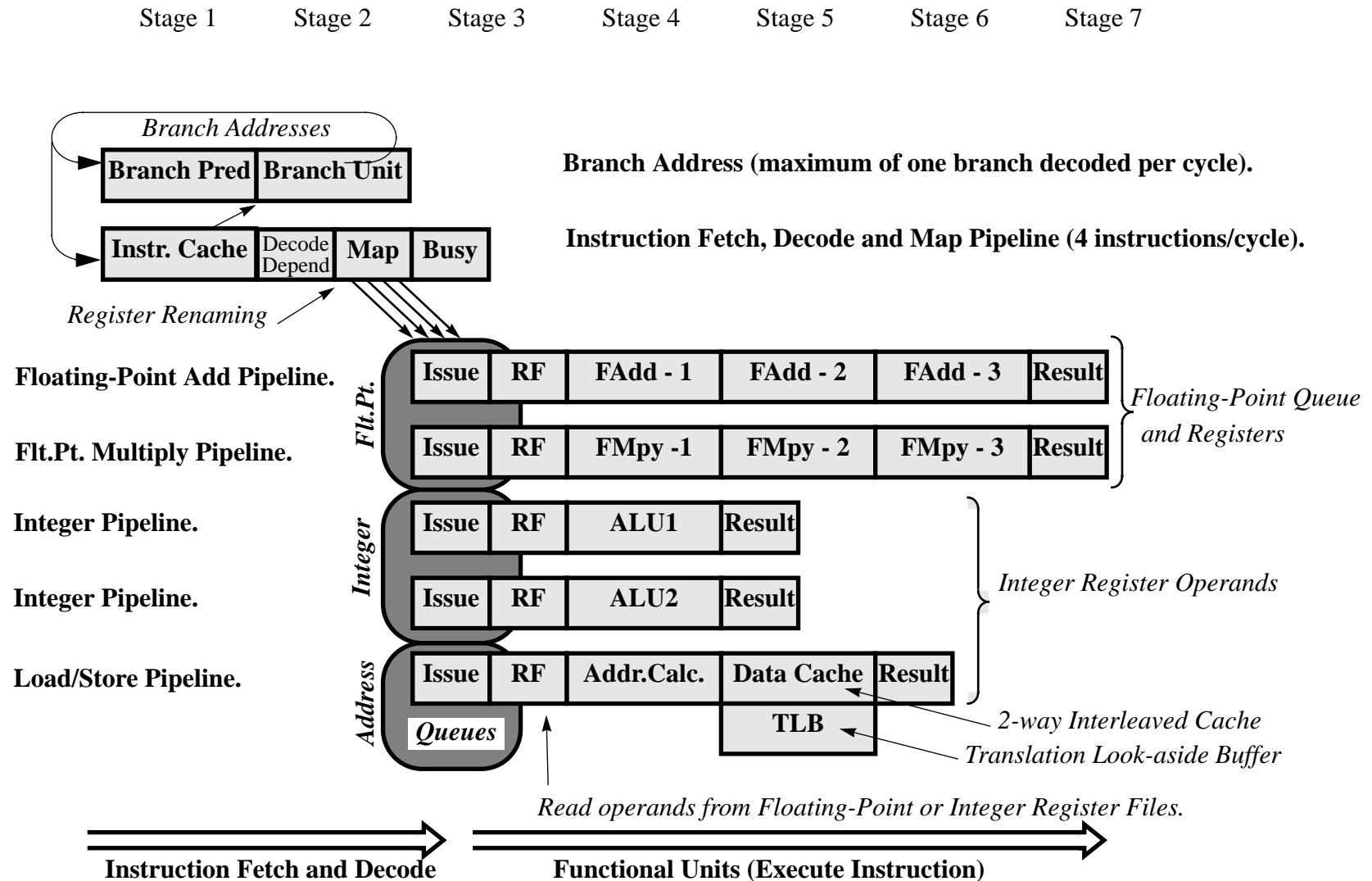




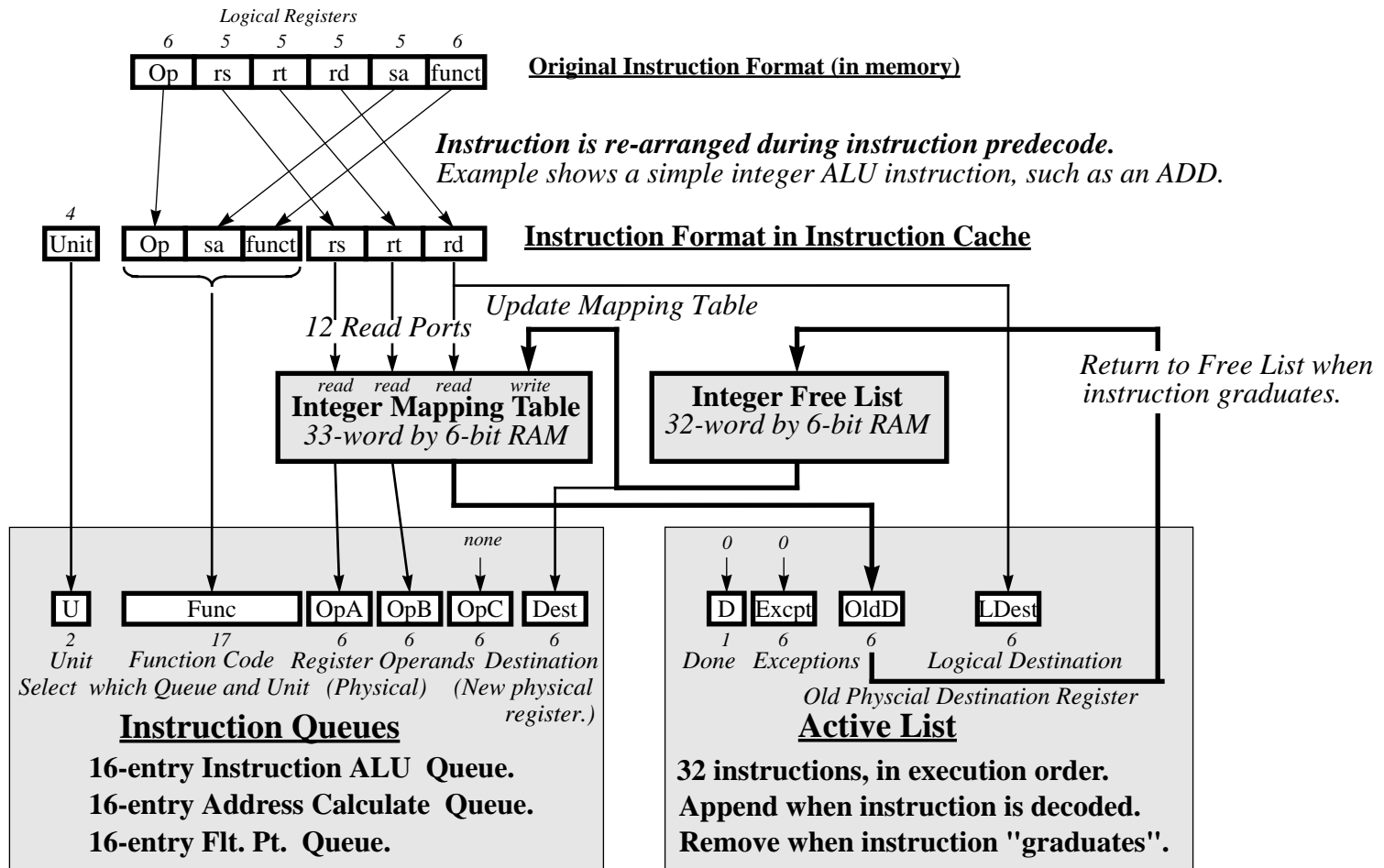
R10000 - Block Diagram



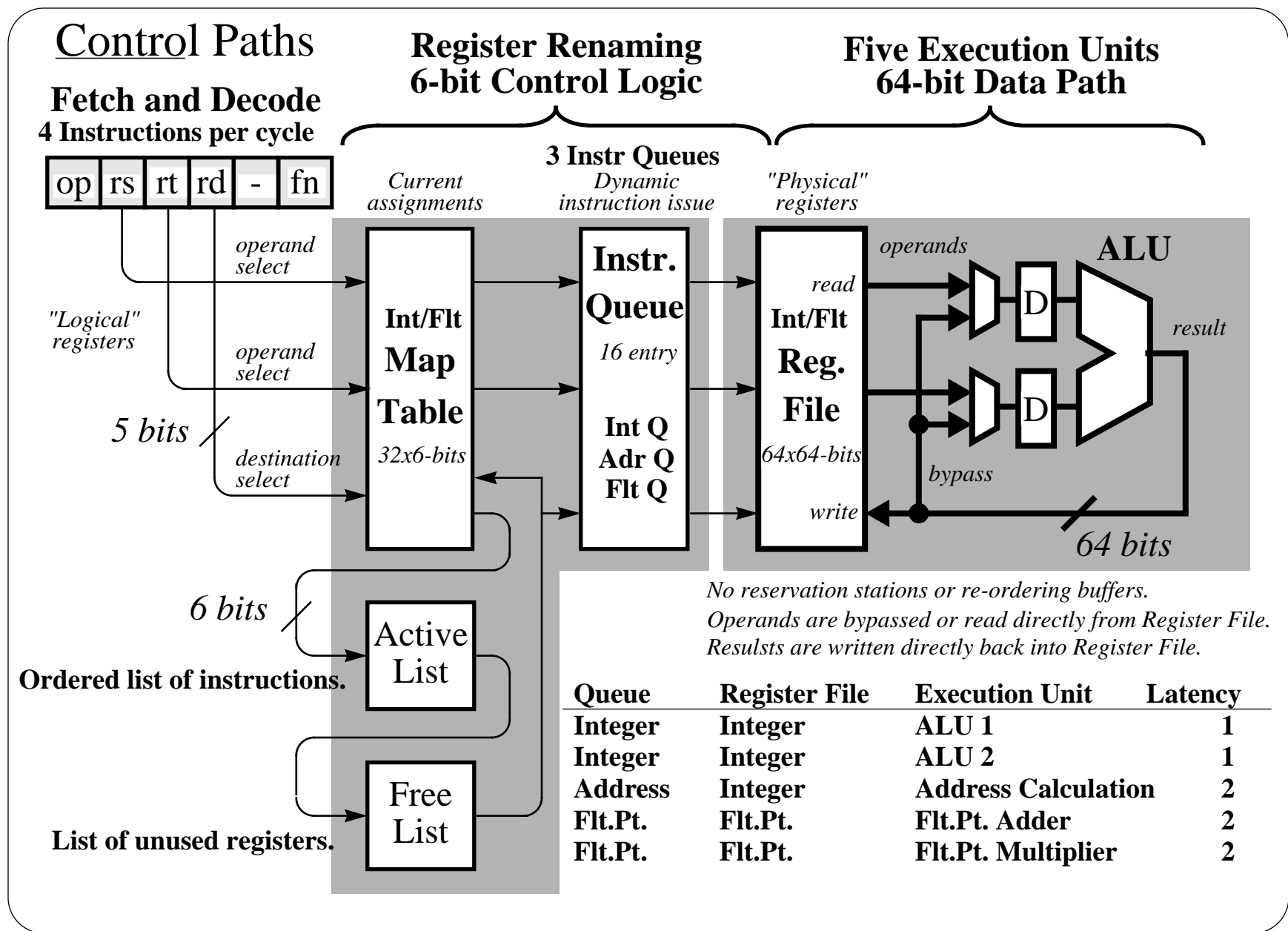
R10000 - Pipelines



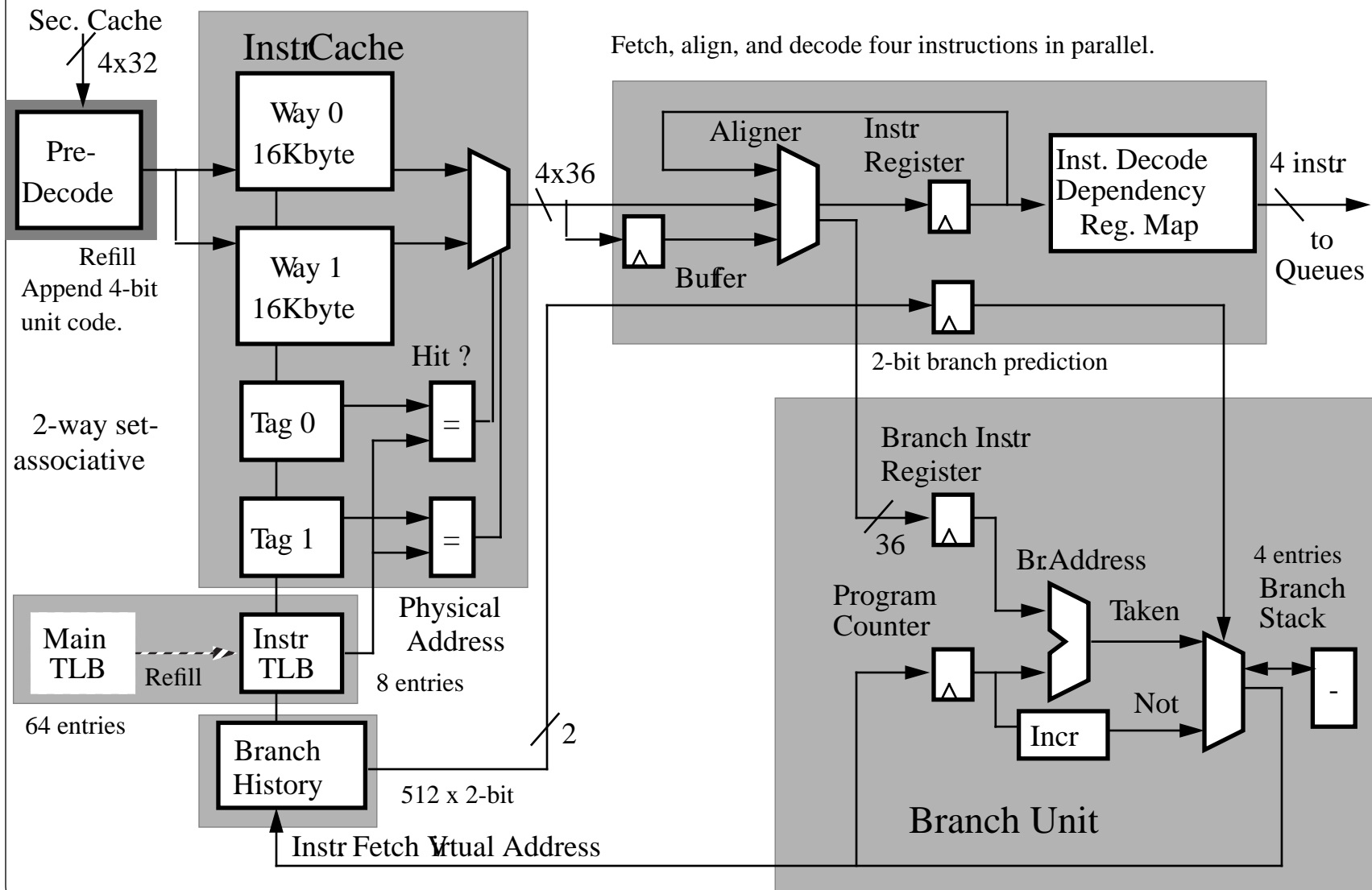
Register Renaming



During any cycle, each physical register number is either in Mapping Table, Active List, or Free List.

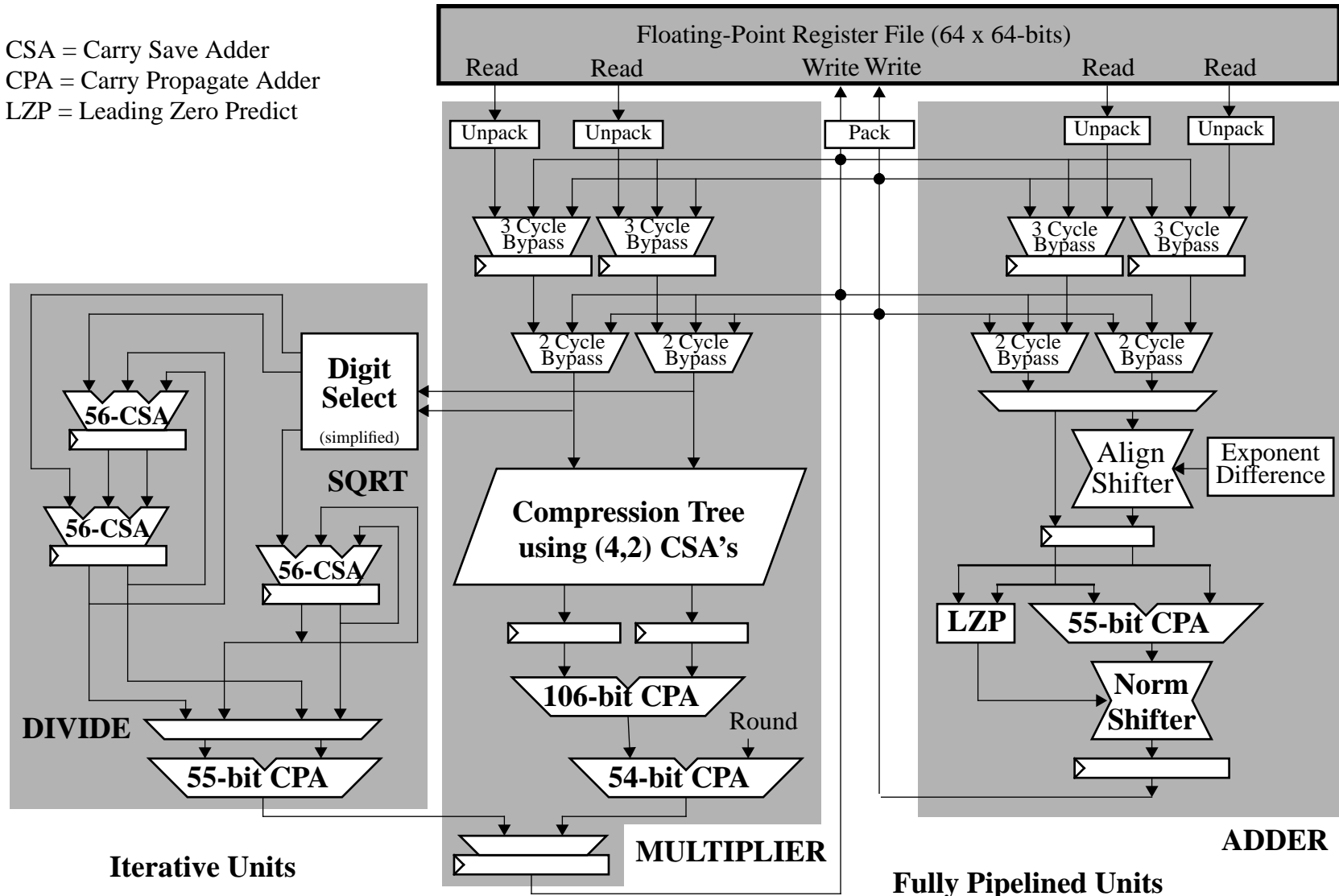


Instruction Fetch and Branch

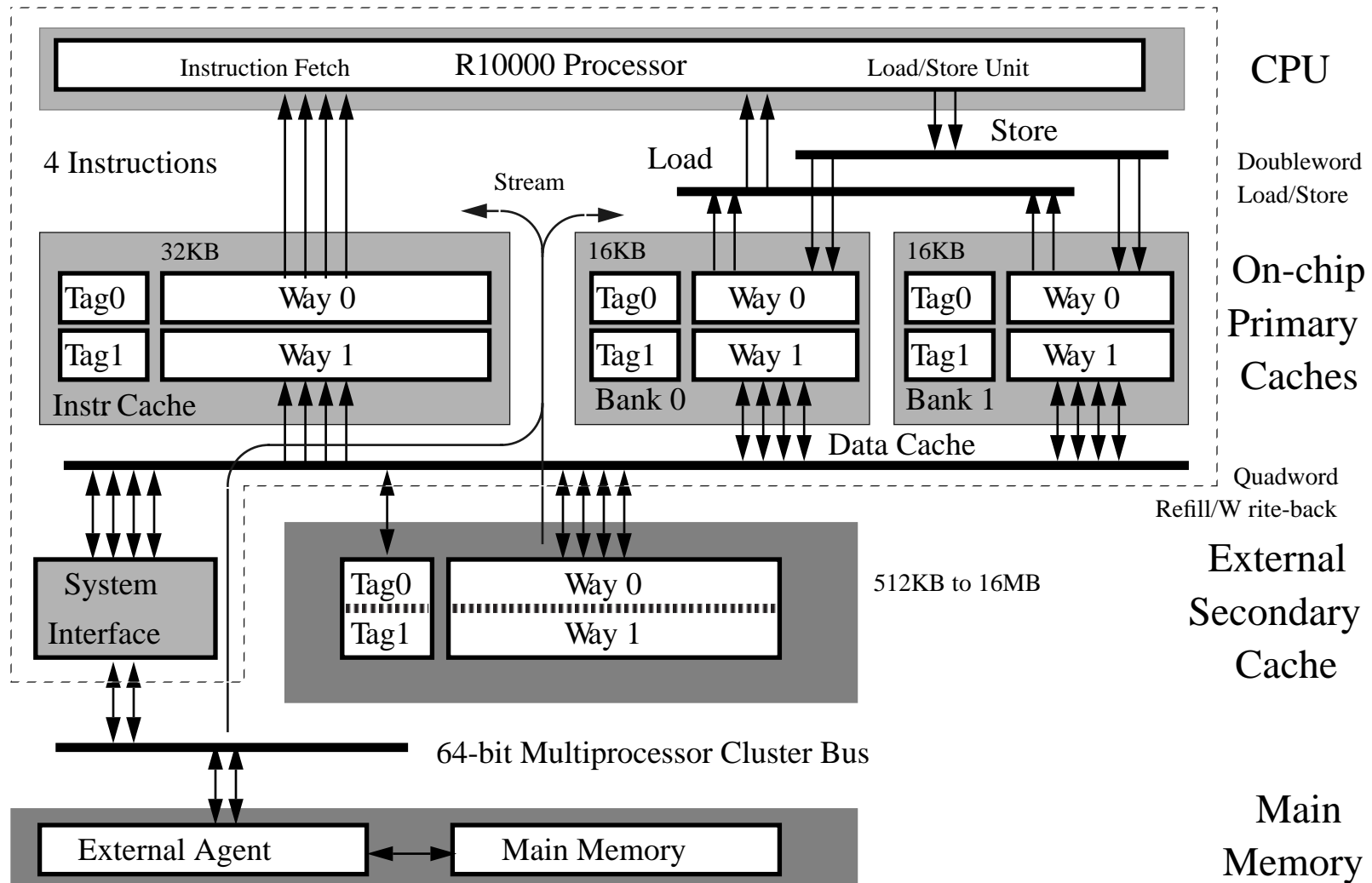


Floating-Point Units

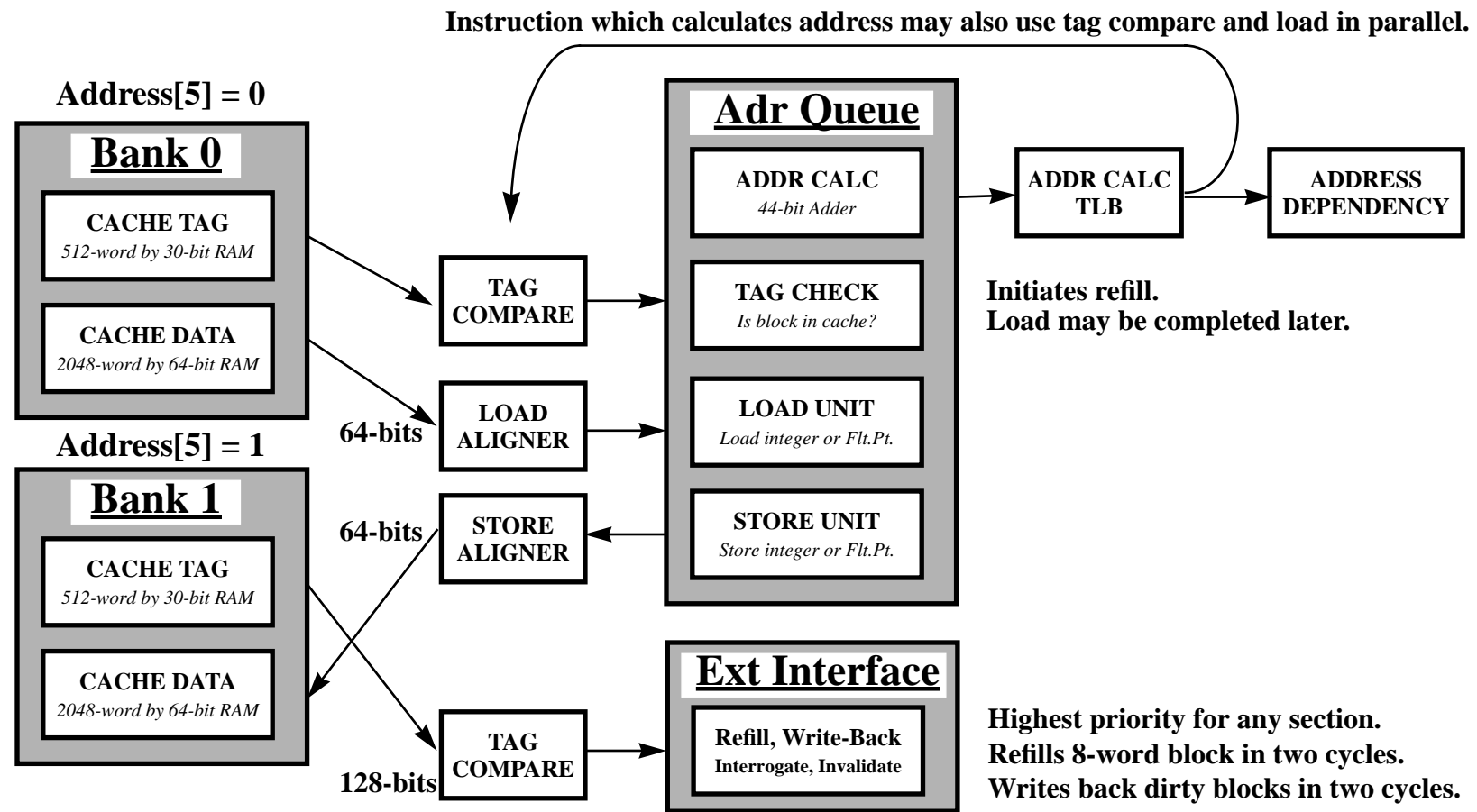
CSA = Carry Save Adder
CPA = Carry Propagate Adder
LZP = Leading Zero Predict



R10000 Memory Hierarchy



Parallelism in Data Cache



Four sections can be independently allocated.

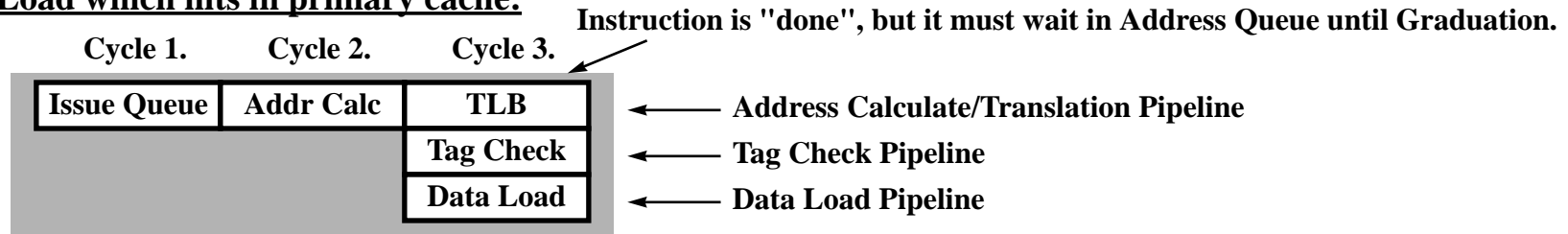
CPU accesses are 64 bits wide, 2-way associative.

Refill and write-back are 128 bits wide. (Way is known.)

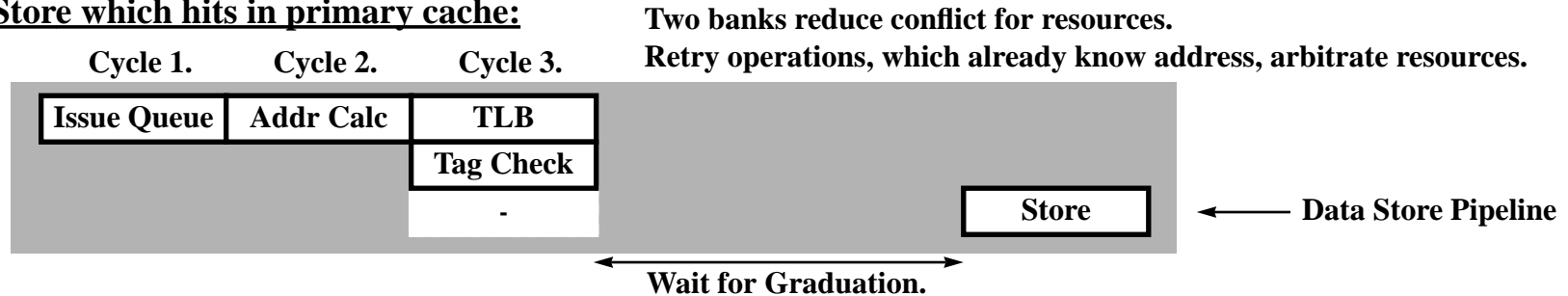
Five control units can operate in parallel, if resources do not collide.

Data Cache Pipelines

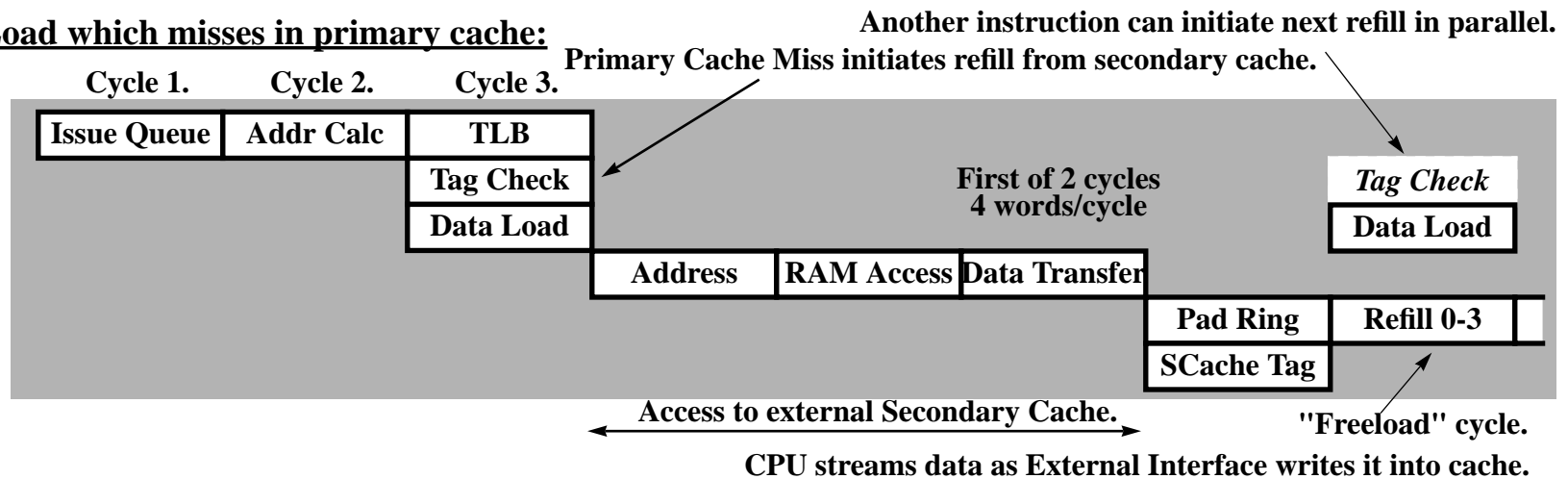
Load which hits in primary cache:



Store which hits in primary cache:



Load which misses in primary cache:



Non-blocking Cache

Concurrent refill times reduce effective cache latency.

Cycles Per Instr (CPI):
(Simulated results)

Spec Benchmarks:

SC

Spread Sheet

compress

File Compression

fpppp

Quantum Chemistry

doduc

Thermal-hydraulic Model

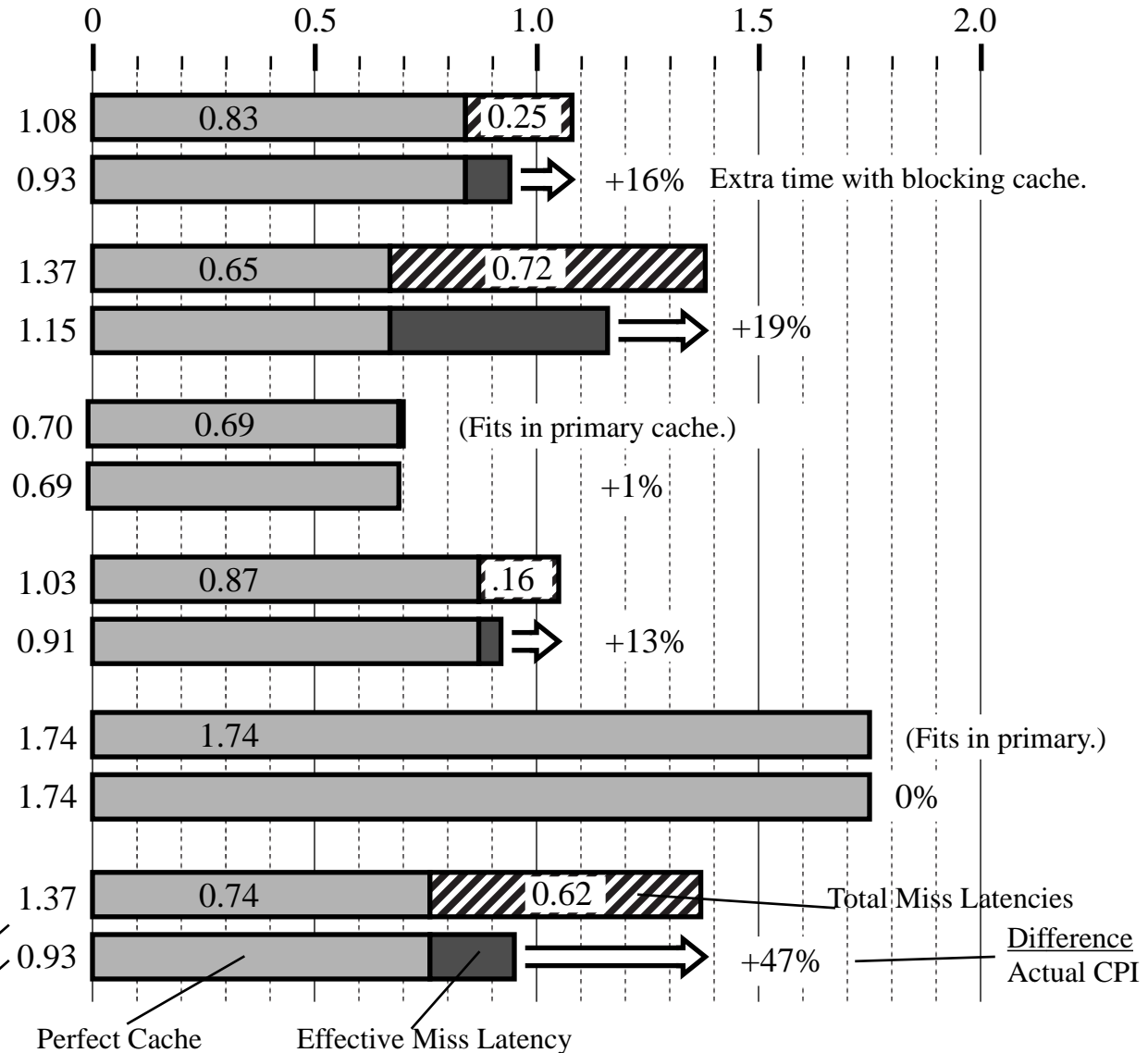
ora

Spherical Ray Tracing
(Reciprocals, Sqr Roots)

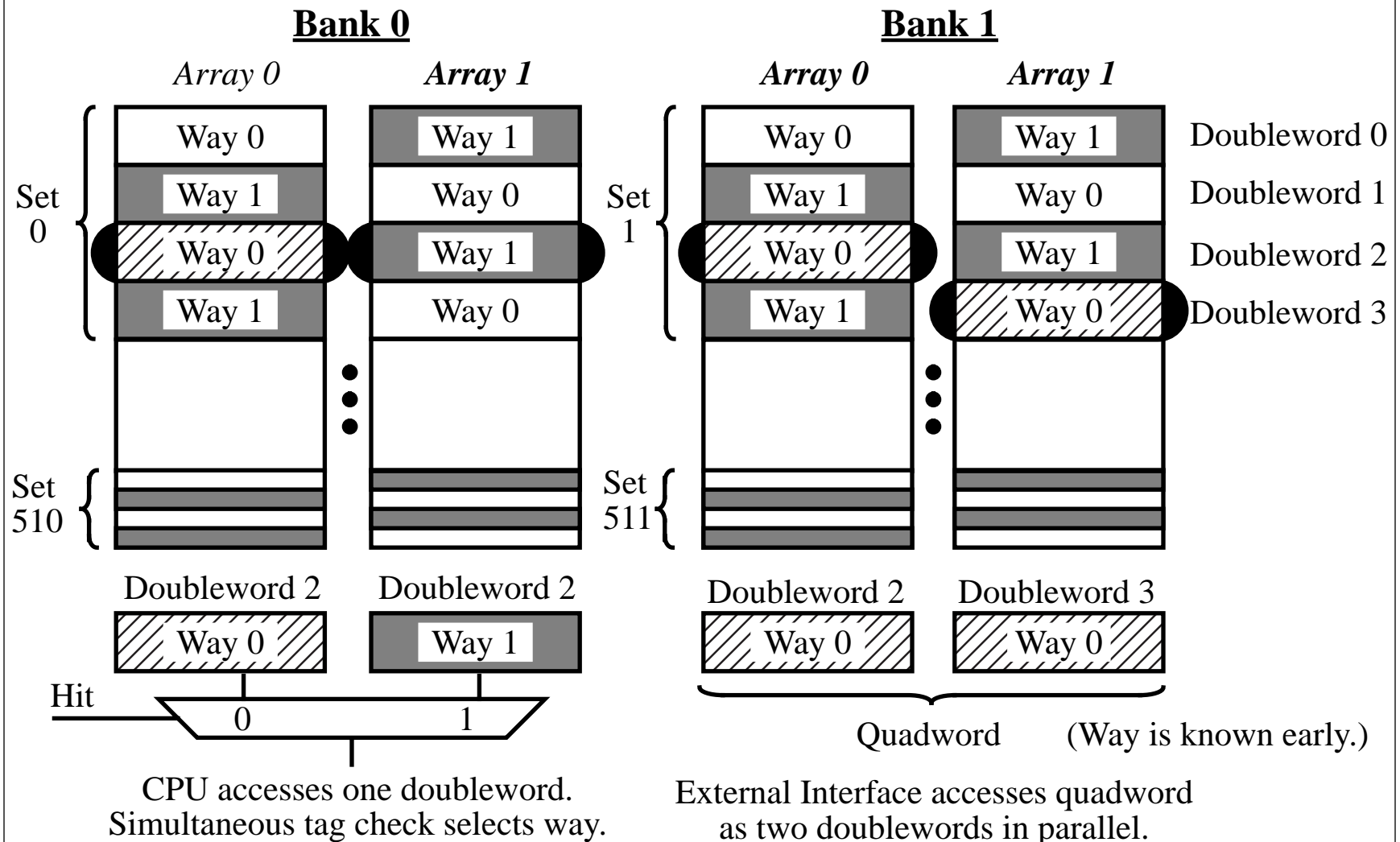
tomcatv

Vector Flt-Pt

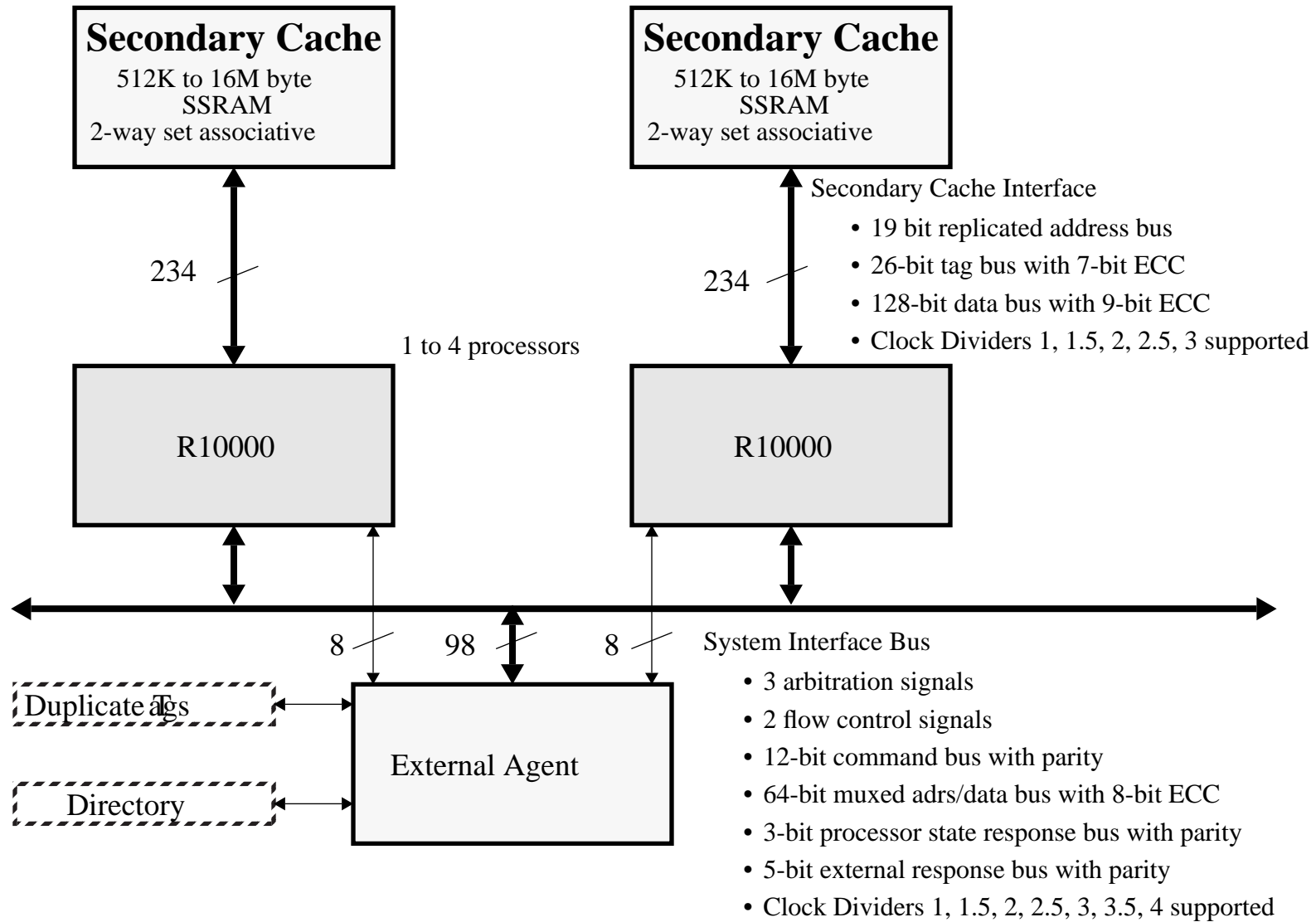
CPI without overlap
Actual R10000 CPI



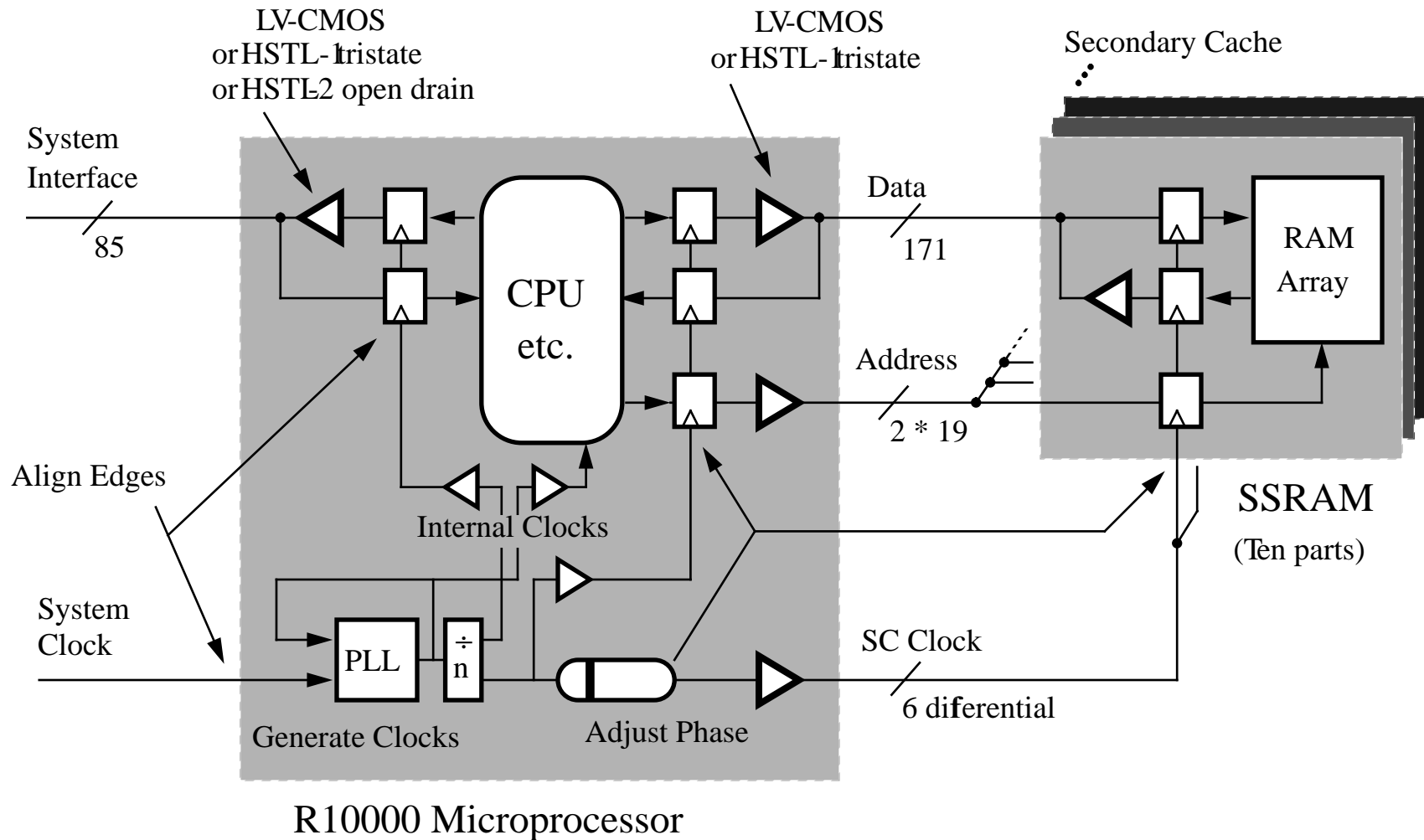
Data Cache Interleaving



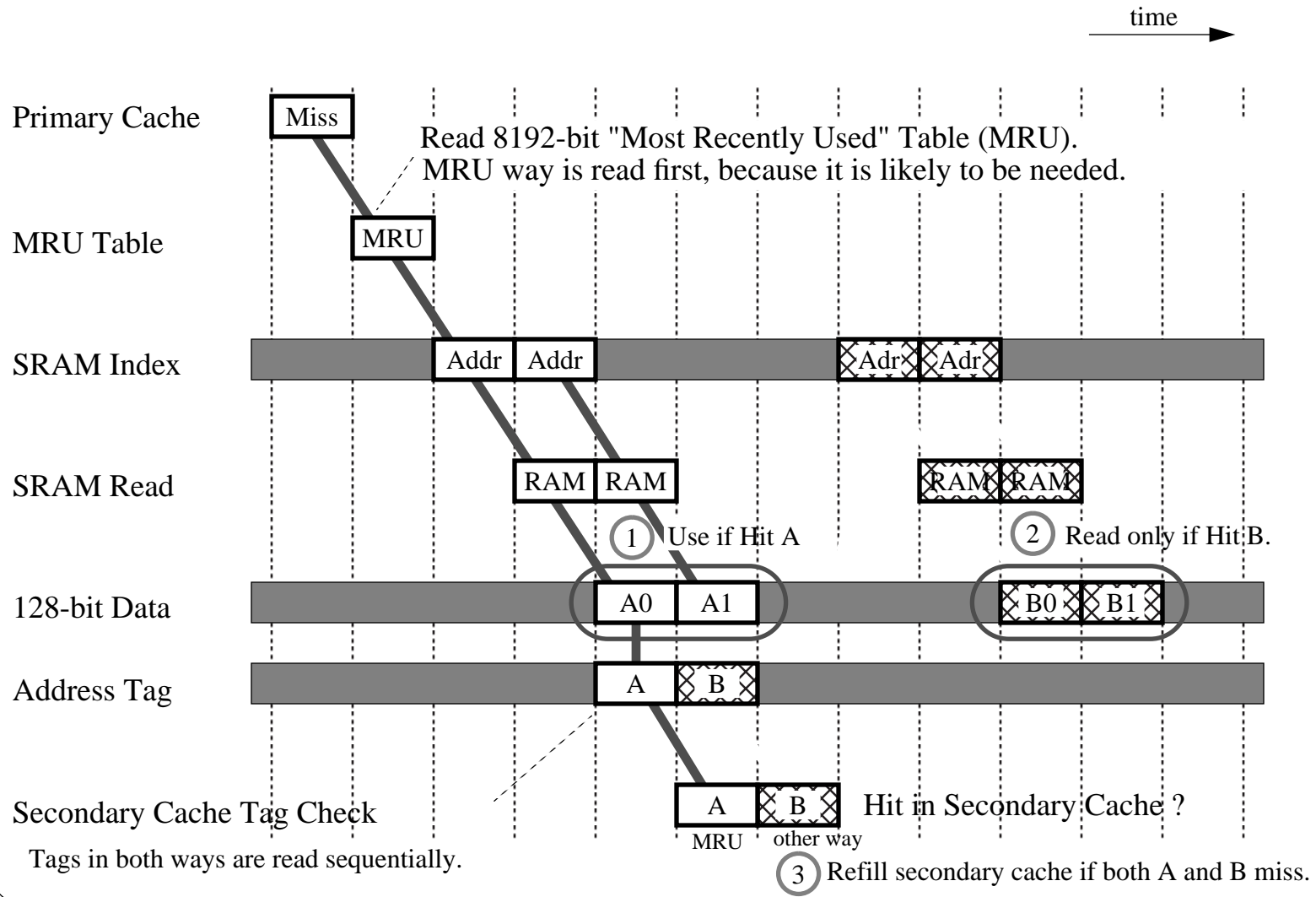
System Configurations



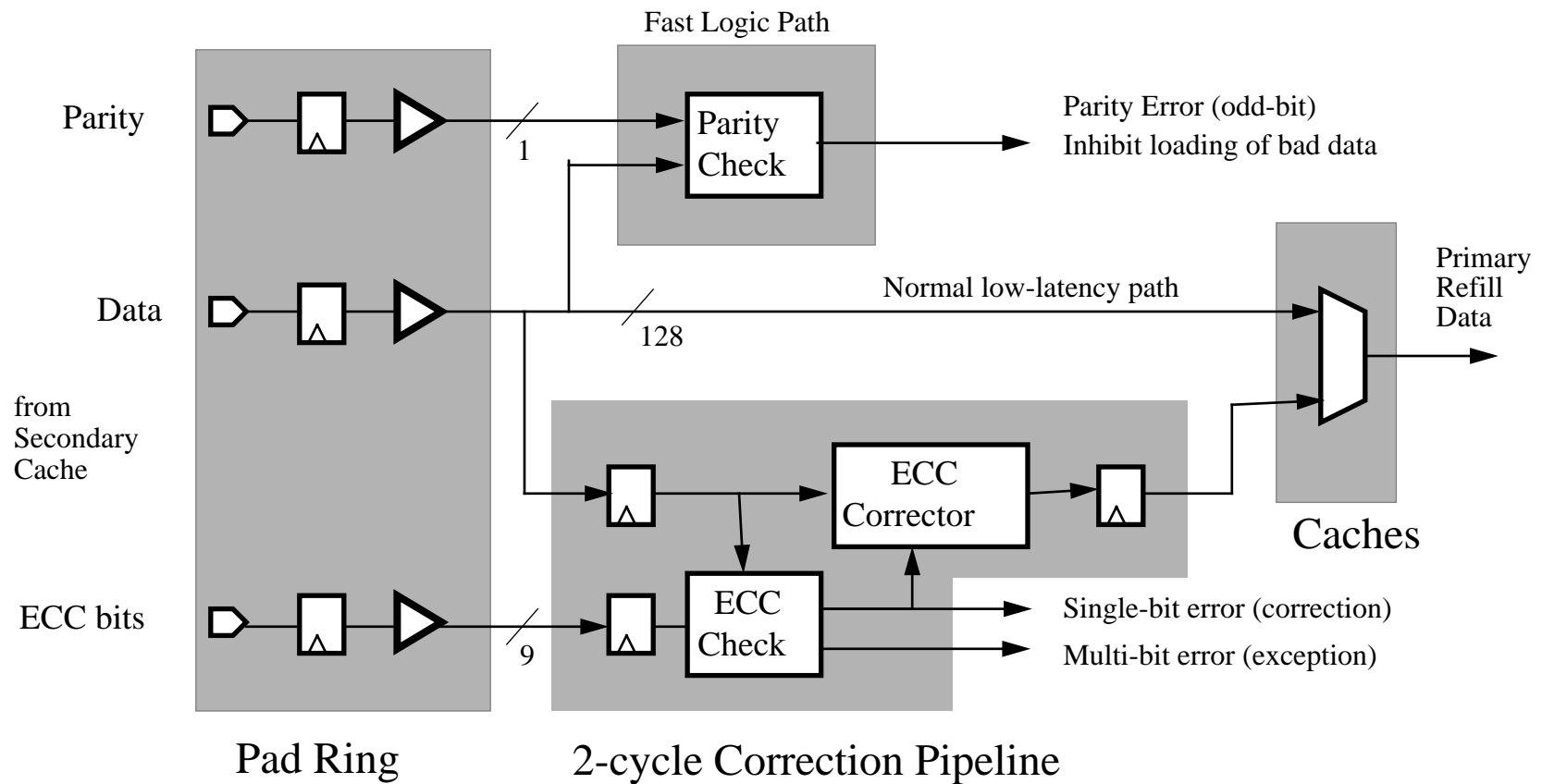
Clocks and Output Drivers



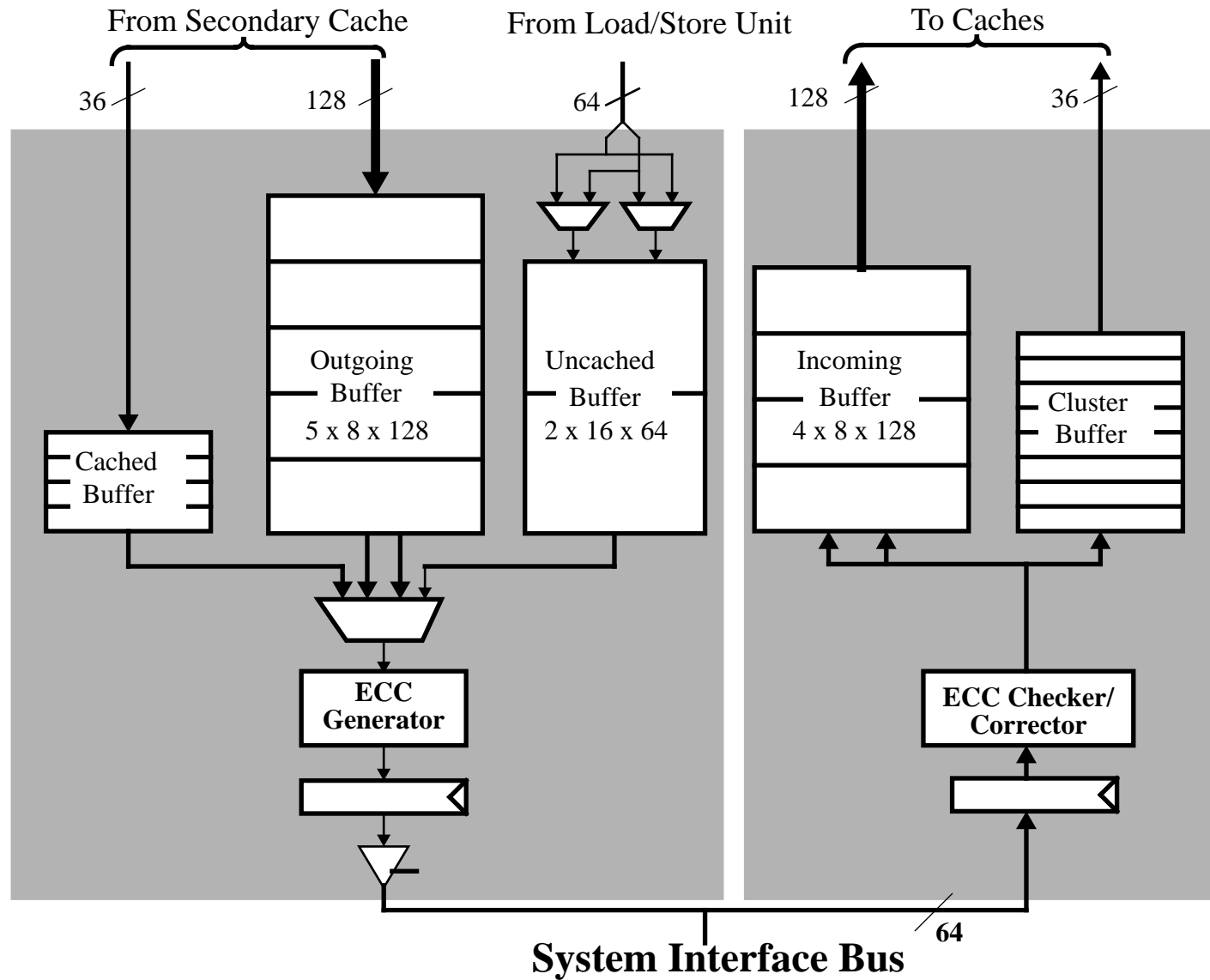
Refill from Set-Associative Secondary Cache



Secondary Cache Error Protection



System Interface Block Diagram



Functional Verification Methodology

- n Tools and environment:
 - n Inhouse HDL and simulator with backup and replay.
 - n Graphical user interface for simulation and regression.
 - n An instruction level simulator as a reference machine, which checks
 - n Architecture registers
 - n Memory hierarchy
 - n Programmable random code generators for UP and MP.
 - n Arc coverage and consistency checking for state machines.
- n C-based System Model supports
 - n Secondary cache array, memory controller and array, bus controller.
 - n Bus protocol checking.
 - n External events :
 - n programmable or purely random
 - n imbedded in diagnostics for fine-grain control
 - n 1 to 4 processor configuration.

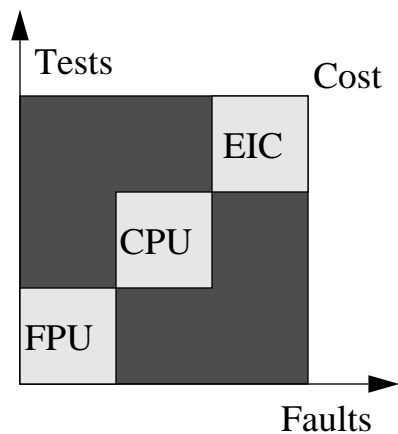
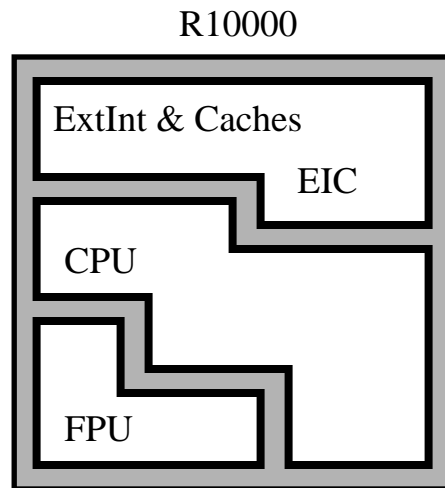


Diagnostic Development

- n Directed Diagnostics
 - n Architecture Verification Programs (AVP)
 - n Microarchitecture Verification Programs (MVP)
 - n Implementation Verification Programs (IVP)
- n Random Diagnostics From Programmable Random Code Generators
 - n Functional unit intensive
 - n Load/Store intensive
 - n Branch intensive
 - n Mix of the above under UP and MP environments
- n Diags are self-checking and/or compared with the reference machine.
- n UP and MP applications.
- n Booting O/S's on R10000 RTL : 2 Unix O/S's and NT.

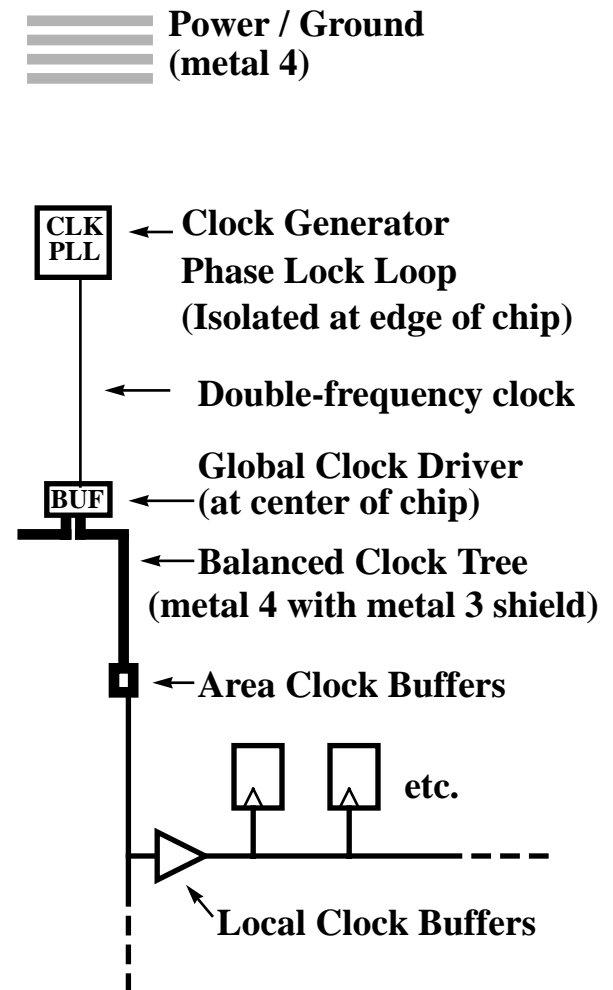
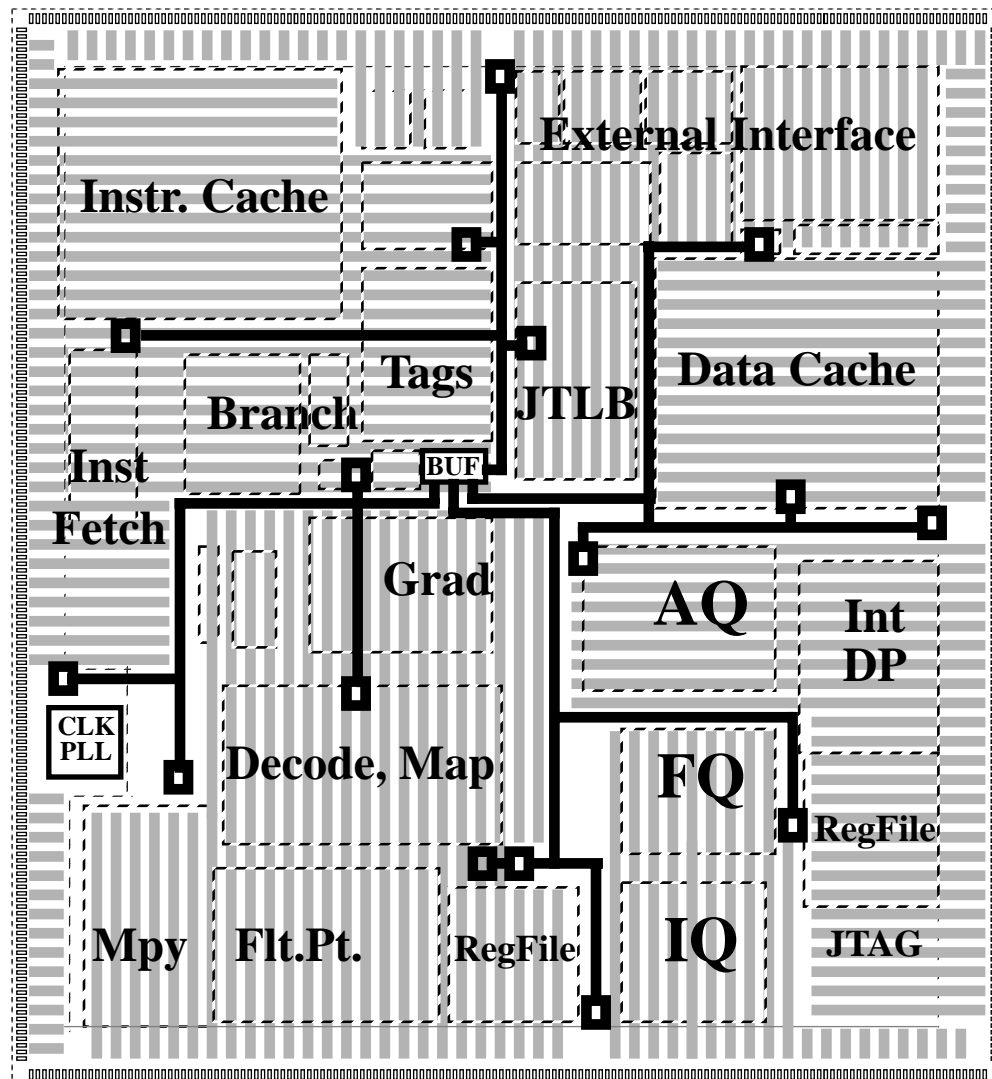


Test Features

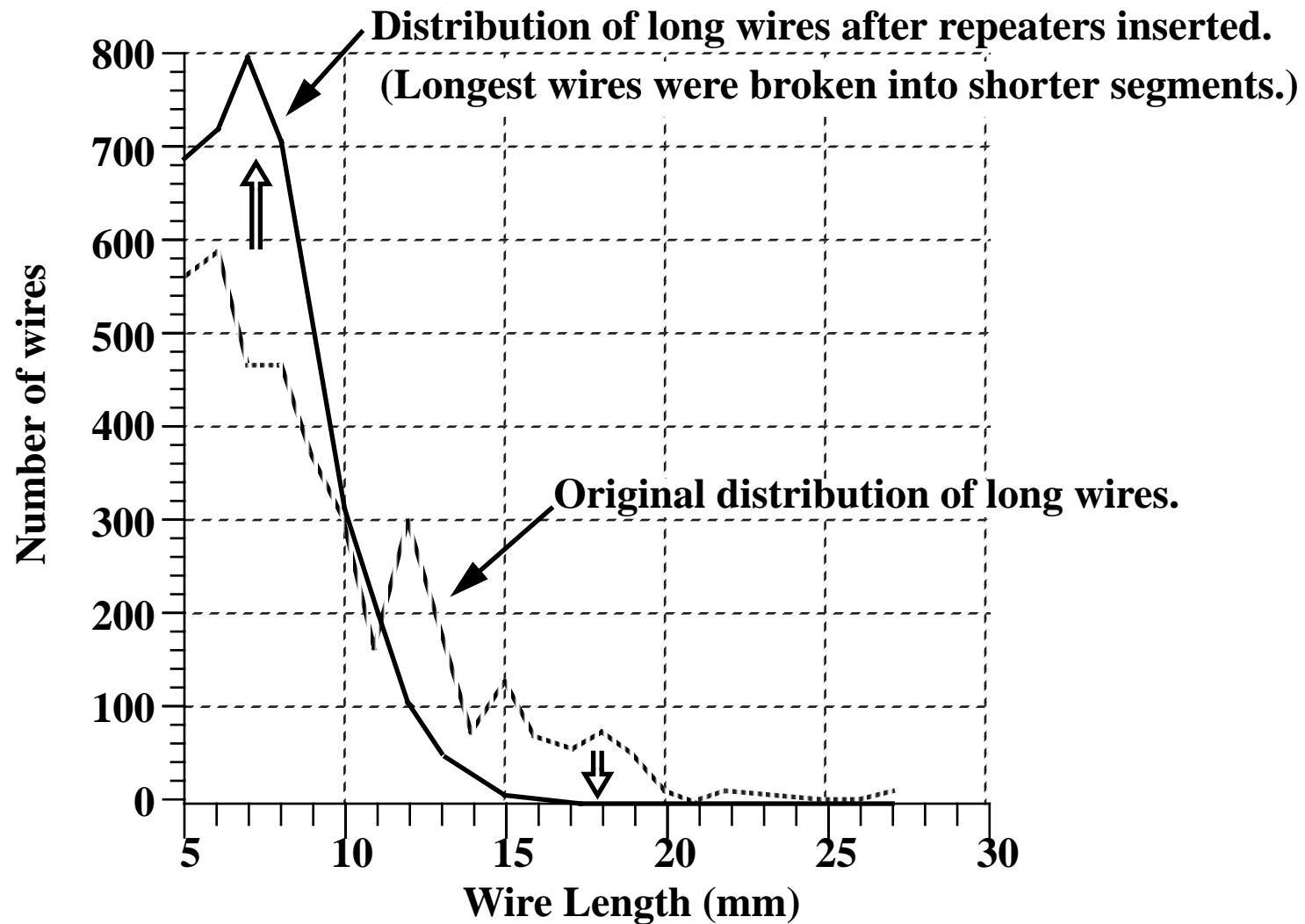


- n On-chip virtual output pins:
 - Physical design partitioning
 - Direct observability of internal signals
 - Signature compression through LFSRs
(Linear-Feedback Shift Register)
- n Dedicated test structures:
 - No performance impact
 - No logic design overhead
 - No special clock requirements
- n Enhanced debug and diagnostics:
 - Cycle-by-cycle sampling of internal signals
 - Observed signals correlate to logic specification
 - Signature analysis
- n Test cost reduction:
 - No special ATE requirements
 - Internal test-output compression by signature
 - Test and fault partitioning.
 - Reduced test time and higher fault coverage

Clock and Power Distribution



Signal Repeaters on Long Wires



R10000 Die Photo

This sheet shows physical placement of major blocks.
(Full color photo slide will be shown at Hot Chips.)

